

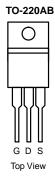
# IPP70P04P4-09-VB Datasheet P-Channel 40-V (D-S) MOSFET

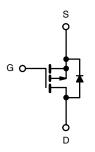
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$r_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
- 40	0.0041 at V <sub>GS</sub> = - 10 V	- 110	185 nC			

#### **FEATURES**

• TrenchFET® Power MOSFET







P-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b>	<b>S</b> T <sub>A</sub> = 25 °C, unle	ss otherwise not	ed		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	- 40	V		
Gate-Source Voltage		V <sub>GS</sub>	± 20		
	T <sub>C</sub> = 25 °C		- 110 <sup>a</sup>		
Continuous Drain Current /T = 175 °C)	T <sub>C</sub> = 70 °C		- 110 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	39 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		33 <sup>b, c</sup>	A	
Pulsed Drain Current		I <sub>DM</sub>	240	_ ^	
Continuous Course Proin Diade Current	T <sub>C</sub> = 25 °C	I.	110		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	l <sub>S</sub> —	10 <sup>b, c</sup>		
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	75		
Single-Pulse Avalanche Energy	L = 0.1 IIII	E <sub>AS</sub>	281	mJ	
	T <sub>C</sub> = 25 °C		375		
Maximum Daylar Dissination	T <sub>C</sub> = 70 °C	D_	262	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	15 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C		10.5 <sup>b, c</sup>		
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		
Soldering Recommendations (Peak Temperature		260			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	$R_{thJA}$	8	10	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	0.33	0.4	- C/VV		

#### Notes:

- a. Package limited.b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 40 °C/W.



Parameter	Symbol Test Conditions		Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 40		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	,		- 5.5		IIIV/ C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 2	- 3	- 4	٧	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zovo Coto Voltogo Dvois Current	1	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V			- 1	μΑ	
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = - 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = -10 \text{ V}$	- 120			Α	
Drain-Source On-State Resistance <sup>a</sup>	r <sub>DS(on)</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 20 A		0.0041		Ω	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 20 A		75		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			11300		pF	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		1510			
Reverse Transfer Capacitance	C <sub>rss</sub>			1000			
Total Gate Charge	$Q_g$			185	280	nC	
Gate-Source Charge	$Q_{gs}$	V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 110 A		48			
Gate-Drain Charge	$Q_{gd}$			42			
Gate Resistance	$R_{g}$	f = 1 MHz		4.0		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			25	40	ns	
Rise Time	t <sub>r</sub>	$V_{DD} = -20 \text{ V}, R_{L} = 0.18 \Omega$		290	440		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 110 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		110	165		
Fall Time	t <sub>f</sub>			35	55		
<b>Drain-Source Body Diode Characteristic</b>	s			1			
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 110	۸	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 240	A	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 20 A		- 0.8	- 1.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			70	105	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 20 A, di/dt = 100 A/μs, T <sub>.I</sub> = 25 °C		130	200	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$\frac{1}{1} = \frac{1}{2} = \frac{1}$		37			
Reverse Recovery Rise Time	t <sub>b</sub>	7		33		ns	

#### Notes:

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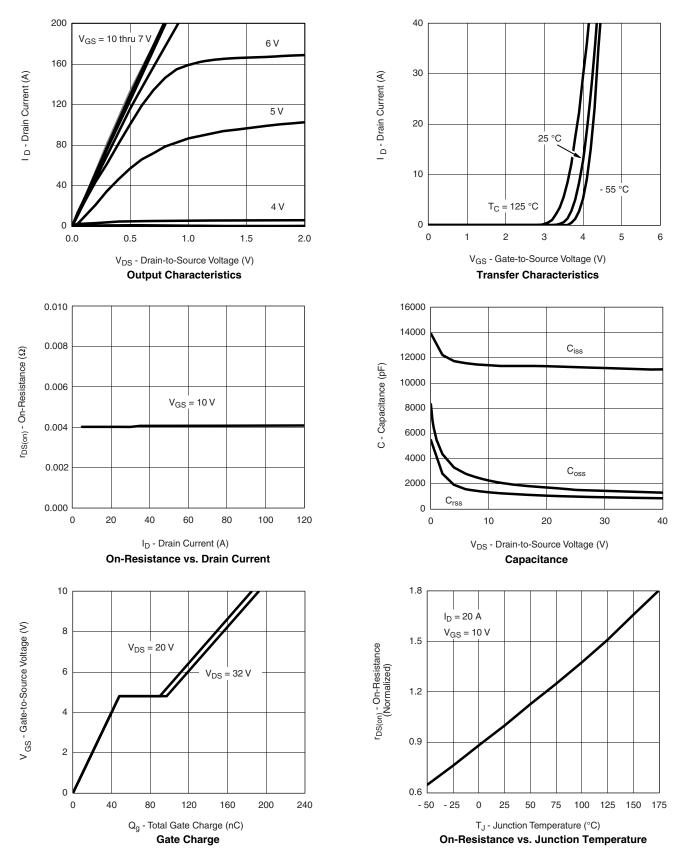
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$ 

b. Guaranteed by design, not subject to production testing.

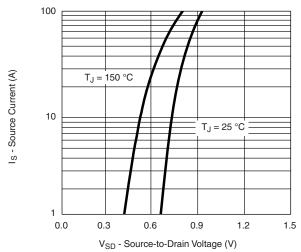


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

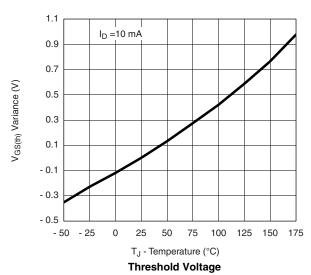


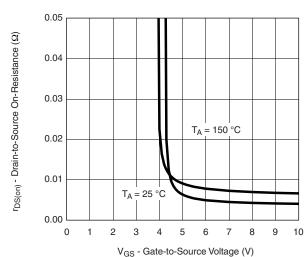


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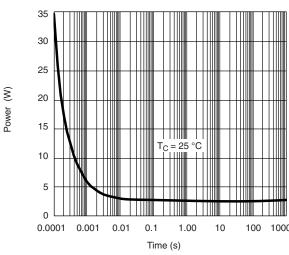


#### Source-Drain Diode Forward Voltage

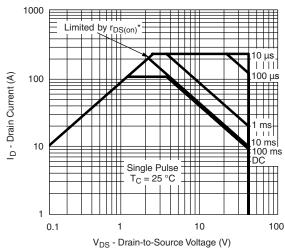




#### On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

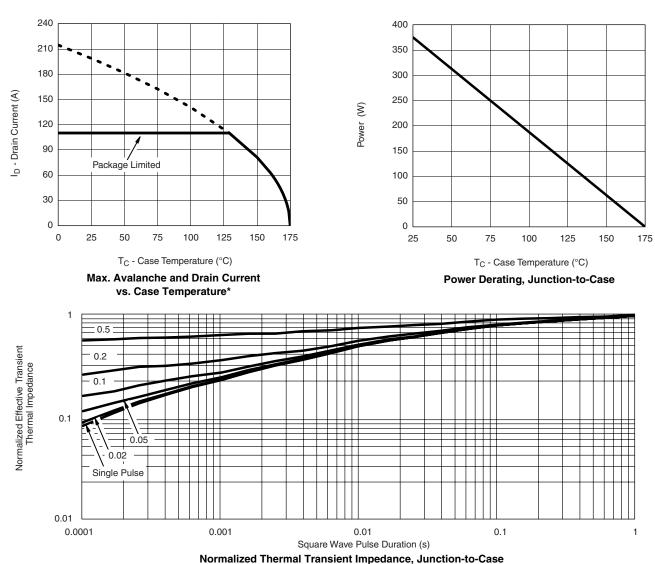


\*V<sub>GS</sub> > minimum V<sub>GS</sub> at which r<sub>DS(on)</sub> is specified

Safe Operating Area, Junction-to-Case



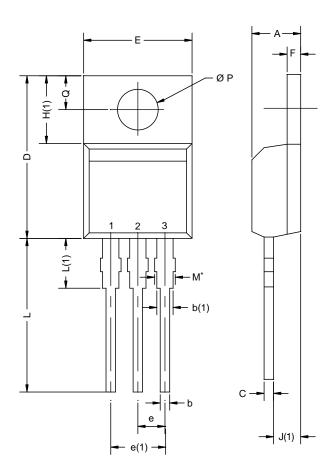
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<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 175$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



### **TO-220AB**



	MILLIM	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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